## Notice of References Cited Application/Control No. 10/536,546 Examiner Lorna M. Douyon Applicant(s)/Patent Under Reexamination PATIEN ET AL. Page 1 of 1

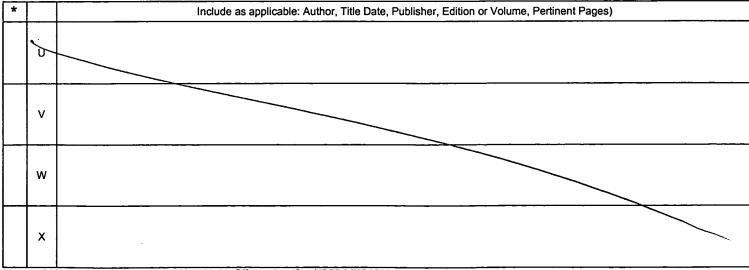
## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-3,490,743	01-1970	SCHMITZ ADOLF; et. al.	510/133
*	В	US-3,557,006	01-1971		510/146
*	С	US-4,992,193	02-1991	Evans, Elfed H.	510/349
*	D	US-5,002,758	03-1991	Ichii et al.	424/44
*	Е	US-5,110,868	05-1992	Bellis et al.	510/193
*	F	US-5,759,974	06-1998	Menke et al.	510/191
*	G	US-5,759,988	06-1998	Heile et al.	510/441
*	Н	US-6,559,110	05-2003	Lopes, John A.	510/141
*	ı	US-2002/0068038	06-2002	Yang, Joo Hwan	424/44
	-	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 62045516-A	02-1987	Japan	Tauchi et al.	
	0					
	Р					
	Q					
	R					
	s					
	Т			·		

## **NON-PATENT DOCUMENTS**



\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.